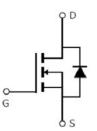


Main Product Characteristics:

V _{DSS}	600V
R _{DS} (on)	3.6ohm(typ.)
I _D	2A







TO220F

Marking and pin
Assignment

Schematic diagram

Features and Benefits:

- Advanced MOSFET process technology
- Special designed for PWM, load switching and general purpose applications
- Ultra low on-resistance with low gate charge
- Fast switching and reverse body recovery
- 150°C operating temperature



Description:

It utilizes the latest processing techniques to achieve the high cell density and reduces the on-resistance with high repetitive avalanche rating. These features combine to make this design an extremely efficient and reliable device for use in power switching application and a wide variety of other applications.

Absolute max Rating:

Symbol	Parameter	Max.	Units	
I _D @ TC = 25°C	Continuous Drain Current, V _{GS} @ 10V①	2		
I _D @ TC = 100°C	Continuous Drain Current, V _{GS} @ 10V①	1.3	Α	
I _{DM}	Pulsed Drain Current②	8		
Pp @TC = 25°C	Power Dissipation③	23	W	
PD @ 1C = 25 C	Linear Derating Factor	0.18	W/°C	
V _{DS}	Drain-Source Voltage	600	V	
V _{GS}	Gate-to-Source Voltage		V	
E _{AS}	Single Pulse Avalanche Energy @ L=55mH		mJ	
I _{AS}	Avalanche Current @ L=55mH	2	А	
T _J T _{STG}	Operating Junction and Storage Temperature Range	-55 to +150	°C	



Thermal Resistance

Symbol	Characterizes	Тур.	Max.	Units
$R_{ heta JC}$	Junction-to-case③	_	5.5	℃W
В	Junction-to-ambient (t $\leq 10s$) (4)	_	62	℃W
$R_{\theta JA}$	Junction-to-Ambient (PCB mounted, steady-state) ④	_	40	°C/W

Electrical Characterizes $@T_A=25^{\circ}C$ unless otherwise specified

Symbol	Parameter	Min.	Тур.	Max.	Units	Conditions
V _{(BR)DSS}	Drain-to-Source breakdown voltage	600	_	_	V	V _{GS} = 0V, ID = 250μA
D	Static Drain-to-Source on-resistance	_	3.6	4	0	V _{GS} =10V,I _D = 1A
$R_{DS(on)}$	Static Drain-to-Source on-resistance	_	8.01	_	Ω	T _J = 125℃
V	Cata threehold voltage	2	_	4	V	$V_{DS} = V_{GS}$, $I_D = 250\mu A$
$V_{GS(th)}$	Gate threshold voltage	_	2.17	_	V	T _J = 125℃
1	Drain to Course leekage gurrent	_	_	1		$V_{DS} = 600V, V_{GS} = 0V$
I _{DSS}	Drain-to-Source leakage current	_	_	50	μA	T _J = 125℃
1	Cata to Source forward lookage	_	_	100	n A	V _{GS} =30V
I _{GSS} Gate-to-Source forwa	Gate-to-Source forward leakage	_	_	-100	nA	V _{GS} = -30V
Q_g	Total gate charge	_	11.5	_	nC	$I_D = 2A$,
Q_{gs}	Gate-to-Source charge	_	2.7	_		V _{DS} =480V,
Q_{gd}	Gate-to-Drain("Miller") charge	_	4.5	_		V _{GS} = 10V
t _{d(on)}	Turn-on delay time	_	9.4	_		V _{GS} =10V, VDS=300V,
t _r	Rise time	_	7.4	_	ns	$R_L=150\Omega$,
t _{d(off)}	Turn-Off delay time	_	25.4	_		$R_{GEN}=25\Omega$
t _f	Fall time	_	20.8	_		ID=2A
C _{iss}	Input capacitance	_	323	_		V _{GS} = 0V
Coss	Output capacitance	_	40	_	pF	V _{DS} = 25V
C _{rss}	Reverse transfer capacitance	_	5	_		f = 1MHz

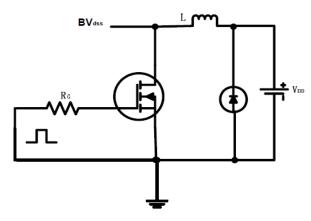
Source-Drain Ratings and Characteristics

Symbol	Parameter	Min.	Тур.	Max.	Units	Conditions
	Continuous Source Current			2	^	MOSFET symbol
Is	(Body Diode)	_		2	A	showing the
I _{SM}	Pulsed Source Current		_	8	А	integral reverse
	(Body Diode)	_				p-n junction diode.
V _{SD}	Diode Forward Voltage	_	0.86	1.3	V	I _S =2A, V _{GS} =0V
t _{rr}	Reverse Recovery Time	_	259.3	1	ns	$T_J = 25$ °C, $I_F = 2A$, $di/dt =$
Q _{rr}	Reverse Recovery Charge	_	1419	_	nC	100A/µs

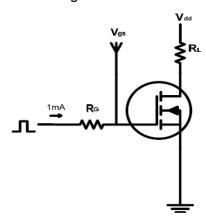


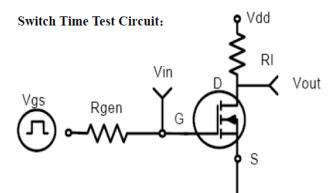
Test circuits and Waveforms

EAS test circuits:

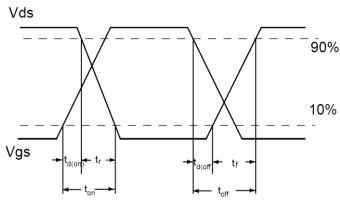


Gate charge test circuit:





Switch Waveforms:

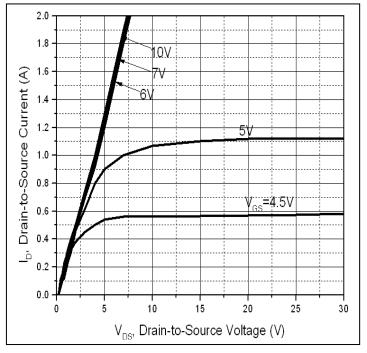


Notes:

- ①The maximum current rating is limited by bond-wires.
- ②Repetitive rating; pulse width limited by max. junction temperature.
- ③The power dissipation PD is based on max. junction temperature, using junction-to-case thermal resistance.
- 4The value of $R_{\theta JA}$ is measured with the device mounted on 1in 2 FR-4 board with 2oz. Copper, in a still air environment with TA =25°C



Typical electrical and thermal characteristics



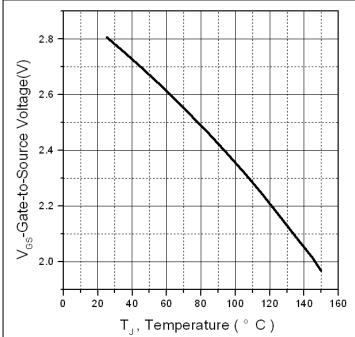
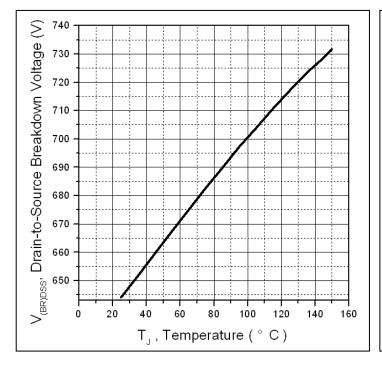


Figure 1: Typical Output Characteristics







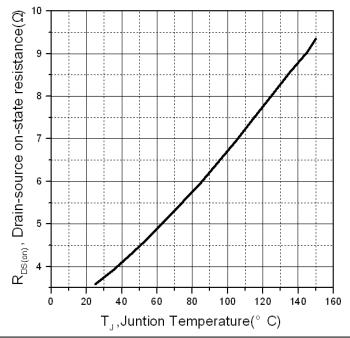
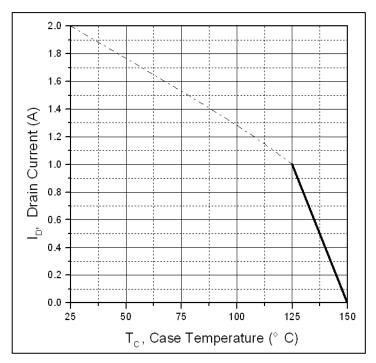


Figure 4: Normalized On-Resistance Vs. Case Temperature



Typical electrical and thermal characteristics



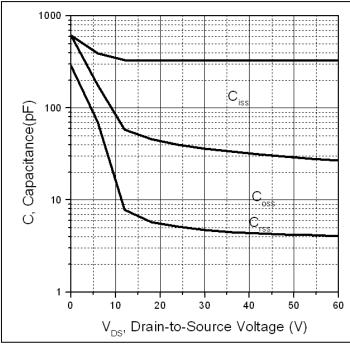


Figure 5. Maximum Drain Current Vs. Case Temperature

Figure 6.Typical Capacitance Vs. Drain-to-Source Voltage

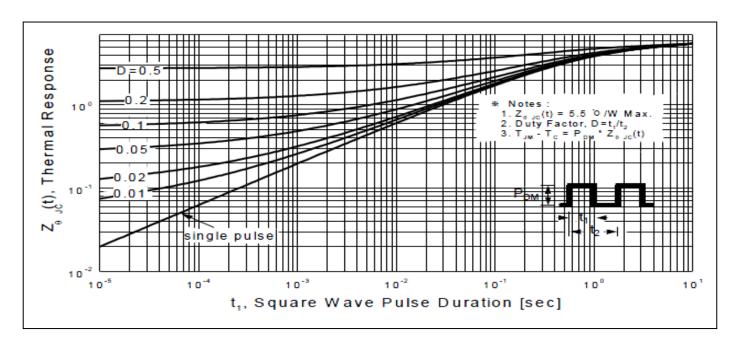
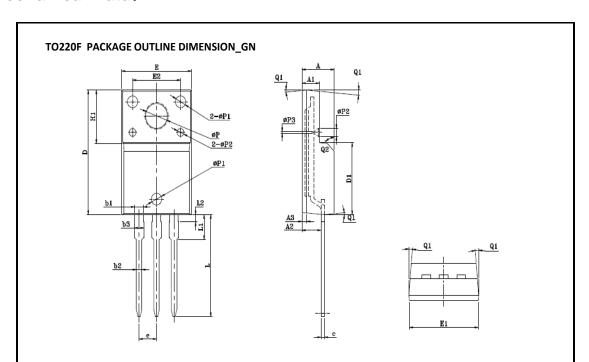


Figure 7. Maximum Effective Transient Thermal Impedance, Junction-to-Case



Mechanical Data:



Comple ed	Dime	ension In Millim	eters	Dimension In Inches			
Symbol	Min	Nom	Max	Min	Nom	Max	
E	9.960	10.160	10.360	0.392	0.400	0.408	
E1	9.840	10.040	10.240	0.387	0.395	0.403	
E2	6.800	7.000	7.200	0.268	0.276	0.283	
Α	4.600	4.700	4.800	0.181	0.185	0.189	
A1	2.440	2.540	2.640	0.096	0.100	0.104	
A2	2.660	2.760	2.860	0.105	0.109	0.113	
A3	0.600	0.700	0.800	0.024	0.028	0.031	
С	-	0.500	-	-	0.020	-	
D	15.780	15.870	15.980	0.621	0.625	0.629	
D1	8.970	9.170	9.370	0.353	0.361	0.369	
H1	6.500	6.700	6.800	0.256	0.264	0.268	
е		2.54BSC		0.10BSC			
ΦР	3.080	3.180	3.280	0.121	0.125	0.129	
ФР1	1.400	1.500	1.600	0.055	0.059	0.063	
ФР2	0.900	1.000	1.100	0.035	0.039	0.043	
ФР3	0.100	0.200	0.300	0.004	0.008	0.012	
L	12.780	12.980	13.180	0.503	0.511	0.519	
L1	2.970	3.170	3.370	0.117	0.125	0.133	
L2	0.830	0.930	1.030	0.033	0.037	0.041	
Q1	3°	5°	7°	3°	5°	7°	
Q2	43°	45°	47°	43°	45°	47°	
b1	1.180	1.280	1.380	0.046	0.050	0.054	
b2	0.760	0.800	0.840	0.030	0.031	0.033	
b3	-	-	1.420	-	-	0.056	





Ordering and Marking Information

Device Marking: SSF2N60F

Package (Available)
TO220F
Operating Temperature Range
C: -55 to 150 °C

Devices per Unit

Package	Units/	Tubes/Inner	Units/Inner	Inner	Units/Carton
Type	Tube	Box	Box	Boxes/Carton	Box
				Box	

Reliability Test Program

Test Item	Conditions	Duration	Sample Size
High	T _j =125℃ to 150℃ @	168 hours	3 lots x 77 devices
Temperature	80% of Max	500 hours	
Reverse	V _{DSS} /V _{CES} /VR	1000 hours	
Bias(HTRB)			
High	T _j =150℃ @ 100% of	168 hours	3 lots x 77 devices
Temperature	Max V _{GSS}	500 hours	
Gate		1000 hours	
Bias(HTGB)			



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